

<b>Notice of References Cited</b>	Application/Control No. 10/518,592	Applicant(s)/Patent Under Reexamination TIDOW ET AL.	
	Examiner Rip A. Lee	Art Unit 1713	Page 1 of 1

□ IDC-US Ref -10

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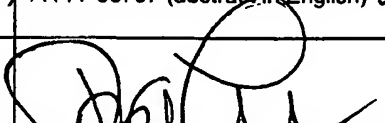
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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